


<b>Search Notes</b>  	<b>Application/Control No.</b>  10049522	<b>Applicant(s)/Patent Under Reexamination</b>  HEYMANN ET AL.
	<b>Examiner</b>  Bhatia, Ajay M	<b>Art Unit</b>  2445

SEARCHED			
Class	Subclass	Date	Examiner
709	218	1/14/2008	AB

SEARCH NOTES		
Search Notes	Date	Examiner
East	1/14/2008	AB
Google Scholar	1/14/2008	AB

INTERFERENCE SEARCH			
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